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In re Application of:

Brian S. Beaman

Atty. Docket: YOR919990088US1

Brian S. Beaman et al.

Art Unit: 2829

Serial No.: 09/251,988

Examiner: Jermele M. Hollington

Filed: February 17, 1999

For: Title **STRUCTURAL DESIGN AND PROCESSES TO CONTROL PROBE
POSITION ACCURACY IN A WAFER TEST PROBE ASSEMBLY**

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

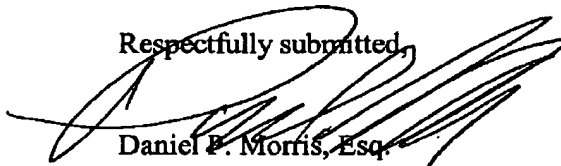
Attached is an Information Disclosure Statement and Notice of Citation of references of relating copending U.S. Application No.: 10/928,473, filed August 27, 2004.

The listing of these materials is not to be construed as an admission that such is actually prior art with respect to the invention of the present application and is not to be construed that such is material with respect to the present invention.

Since these documents are being submitted with an Request for Continued Examination request, applicants believe no fee is due.

Please charge any fee necessary to enter this paper and any previous paper to deposit account 09-0468.

Respectfully submitted,



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Yorktown Heights, NY 10598
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Date: April 24, 2006

Serial Number: 09/251,988

INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)		DocId Number (Optional) FIS920030301		Application Number 10/928,473				
Applicant(s) Beaman, et al.		Filing Date 08/27/04		Group Art Unit 2833				
U.S. PATENT DOCUMENTS								
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
LT		6,452,406	09/17/2002	Beaman, et al.				
LT		6,528,984	03/04/2003	Beaman, et al.				
U.S. PATENT APPLICATION PUBLICATIONS								
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
FOREIGN PATENT DOCUMENTS								
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)								
LT		US Application: 09/254/769 Title: Wafer Scale High Density Probe Assembly, Apparatus For Use Thereof And Methods Of Fabrication Thereof Filing Date: 03/11/1999 Name: Lauro, et al.						
LT		US Application: 08/754/831 Title: High Temperature Chip Test Probe Filing Date: 11/20/1996 Name: Lauro, et al.						
EXAMINER <i>Donna Hume</i>				DATE CONSIDERED <i>08/25/05</i>				
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

PTQ/53/08A (10-95)

Substitute for Form 1449W/PTD INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)		Complete if Known Application Number: 10928,479 Filing Date: August 28, 2004 First Named Inventor: Do-Yuan Shih Group Ad Unit: 2033 Examiner Name: Not Yet Assigned Attorney Docket Number: F18928030301US1	
Sheet	1	of	1

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Examiner Signature	<i>Karver Hance</i>	Date Considered	08/25/05
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* Unique citation designation number. ¹ See attached kinds of U.S. Patent Documents. ² Enter Office that issued the document, by the two-letter code (WIPO Standard 87.3). ³ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁴ Kinds of document by the appropriate symbol(s) as indicated on the document under WIPO Standard 87.16 if possible. ⁵ Applicant is to place a check mark here if English language translation is attached.

Notice of References Cited	Application/Control No. 10/928,473	Applicant(s)/Patent Under Reexamination BEAMAN ET AL	
	Examiner Larisa Z. Tsukerman	Art Unit 2833	Page 1 of 2

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,356,098	03-2002	Akram et al.	324/765
	B	US-6,736,665	05-2004	Zhou et al.	439/482
	C	US-6,278,284	08-2001	Mori et al.	324/755
	D	US-6,838,097	10-2003	Wu et al.	439/482
	E	US-5,404,282	04-1995	Klinke et al.	362/249
	F	US-4,949,224	08-1990	Yamamura et al.	361/784
	G	US-6,920,689	07-2005	Khandros et al.	29/860
	H	US-4,788,496	11-1988	Maetzer et al.	324/754
	I	US-6,024,579	02-2000	Bennett, Glenn Edward	439/66
	J	US-6,255,832	07-2001	Notohardjono et al.	324/754
	K	US-6,292,003	09-2001	Fredrickson et al.	324/754
	L	US-5,399,982	03-1995	Driller et al.	324/754
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	P					
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Notice of References Cited

Part of Paper No. 20050802

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	Examiner Larisa Z. Tsukerman	Art Unit 2833	Page 2 of 2

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	A	US-6,825,422	11-2004	Eldridge et al.	174/260
	B	US-6,869,289	03-2005	Sabatier et al.	439/66
	C	US-4,863,822	10-1990	Prokopp, Manfred	324/758
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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